

Application/Control No

10/758,983

Examiner

Patricia T. Nguyen

Applicant(s)/Patent under Reexamination

YAMAKAWA ET AL.

Art Unit

2817

ORIGINAL CLASS CLASS							SSUE CLASSIFICATION CROSS REFERENCE(S) SUBCLASS (ONE SUBCLASS PER BLOCK)										
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 (Assistant Examiner) (Date)							PRIM	RICIA NG ARY EXA	MINER	Total Claims Allowed: 25							
(Legal Instruments Examiner) (Date)							Paţricia Patracă (Prin	a Nguyer へ Ng nary Examine	10/15 1192	O.G. Print Claim(s)	O.G. Print Fig 24						

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